## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Priority Application Serial No	
Priority Filing Date	August 30, 2001
Inventor	
Assignee	Micron Technology, Inc.
Priority Group Art Unit	
Priority Examiner	
Attorney's Docket No	•
Title: Perovskite-Type Material Forming M	
Methods, and Capacitor Cons	· · · · · · · · · · · · · · · · · · ·

## <u>INFORMATION DISCLOSURE STATEMENT</u> <u>PURSUANT TO 37 C.F.R. " 1.56, 1.97 AND 1.98</u>

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. No admission is made regarding whether all the submitted references are prior art.

The listed references were cited by, or submitted to, the Office in the parent, co-pending application of the above-identified application. The above-identified application is a continuation application of co-pending application Serial No. 09/945,167, filed August 30, 2001. Such prior disclosure is sufficient for the above-identified application as far as copies of the references are concerned. 37 C.F.R. § 1.98(d) and MPEP § 609(2).

Citation of these references is respectfully requested.

Dated:	29 Jan 2004	By:	LIQL	
_		•	James E. Lake Reg. No. 44.854	•

Respectfully submitted,

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE Priority SERIAL NO. 09/945.137 Form PTO-1449 ATTY. DOCKET NO. MI22-2496 LIST OF ART CITED BY APPLICANT APPLICANT (Use several sheets if necessary) Jerome Eldridge Priority GROUP Priority FILING DATE August 30, 2001 U.S. PATENT DOCUMENTS \*Examiner Initial Date Subclass Filing Date
If Appropriate Document Name Class Number 5,350,738 Hase et al AA ΑB 5,272,341 12/93 Micheli et al AC 5,142,437 08/92 Kammerdiner et al AD 6,461,931 10/02 Eldridge Jeon, Yoo Chan ΑE 6,025,257 02/00 AF 08/98 Chivukula 5,789,268 10/02 Eldridge AG 6,461,931 ΑH 6,403,441 06/02 Takehiro et al ΑI 5,953,619 09/99 Miyazawa ΑJ FOREIGN PATENT DOCUMENTS Subclass Date Translation Document Country Number ΑK EP 0727832 A1 08/96 EPO/Miyashita et al ΑL ΑM ΑN ΑP OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) AP John Baliga, "New Materials Enhance Memory Performance", Semiconductor International, November 1999, pgs. 1-8. AQ Advances in Ultrathin Oxides and Oxynitrides I", Materials Research Society Symposium Proceedings Series, Vol. 567,, April 5, 1999, 2 pages. K.S. Tang, W.S. Lau, and G.S. Samudra, "Trends in Dram Dielectrics", IEEE Circuits & Devices, Vol. 13, No. 3, May 1997, pgs. 27-34 AR DATE CONSIDERED EXAMINER \*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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